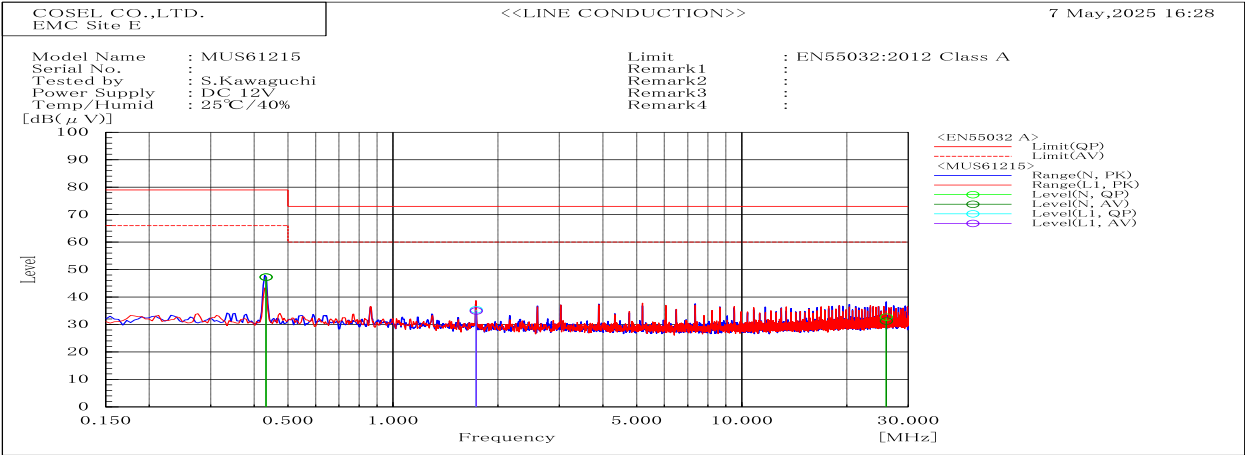
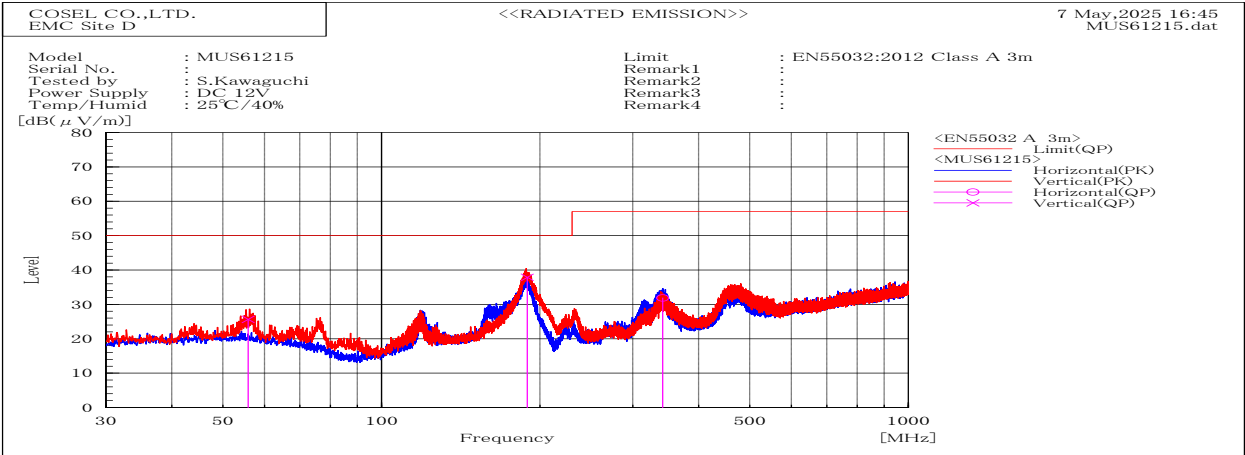


DATA SHEET		Date	07-May-25
Model	MUS61215	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



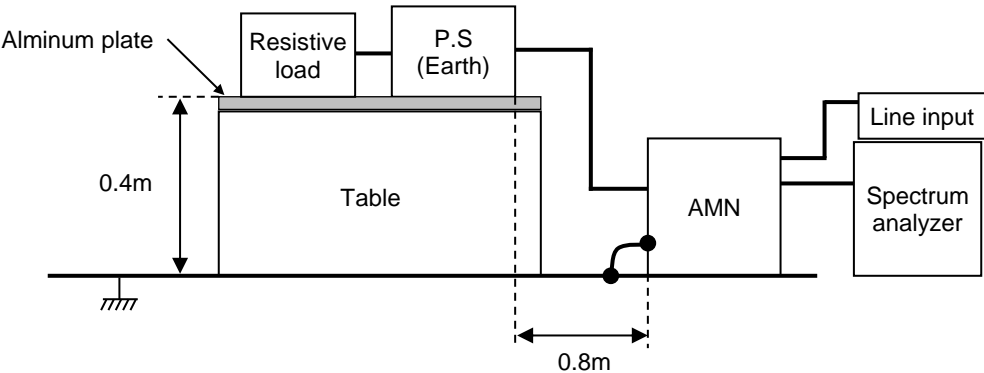
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.733	L1	35.4	34.9	73	60	37.6	25.1	Pass	
0.433	N	47.3	47.3	79	66	31.7	18.7	Pass	
25.984	N	32.7	31.2	73	60	40.3	28.8	Pass	



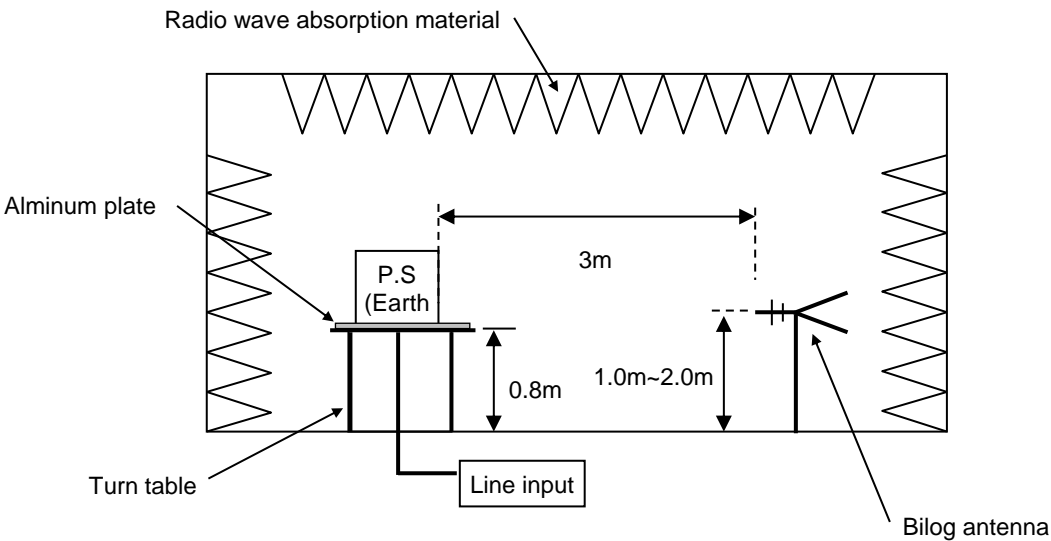
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
189.178	V	Stable	37.9	50	12.1	Pass	100	0	
55.858	V	Stable	25.6	50	24.4	Pass	122	358.6	
341.623	H	Stable	31.9	57	25.1	Pass	108.2	89.2	

DATA SHEET		Date	07-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

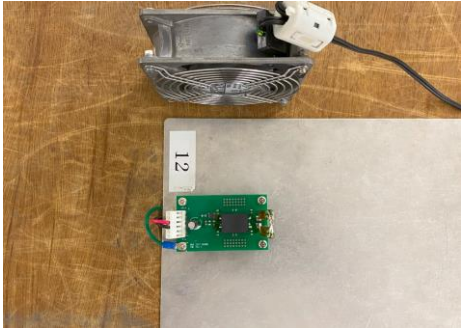
Test : EMI
Model Name: MUS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

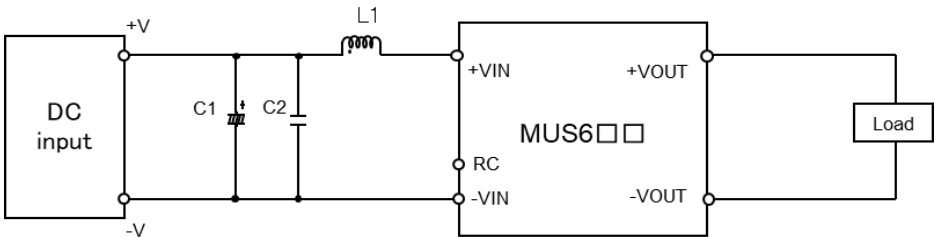


Fig.1 MUS6□□ Testing circuitry

C1 :	MUS605□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS612□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS624□	—	
	MUS648□	—	
C2 :	MUS605□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS612□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS624□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS648□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS605□	6500mA 1.5 μ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUS612□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS624□	2600mA 10 μ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUS648□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)